September 1997

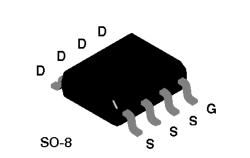


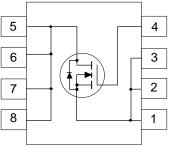
NDS8426 Single N-Channel Enhancement Mode Field Effect Transistor

General Description

Features

- These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as notebook computer power management and other battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.
- $\begin{array}{l} \bullet \quad 9.9 \text{ A, } 20 \text{ V. } \text{R}_{\text{DS(ON)}} = 0.015 \ \Omega \quad @ \ \text{V}_{\text{GS}} = 4.5 \text{ V.} \\ \text{R}_{\text{DS(ON)}} = 0.020 \ \Omega \quad @ \ \text{V}_{\text{GS}} = 2.7 \text{ V.} \end{array}$
- High density cell design for extremely low R_{DS(ON)}.
- High power and current handling capability in a widely used surface mount package.



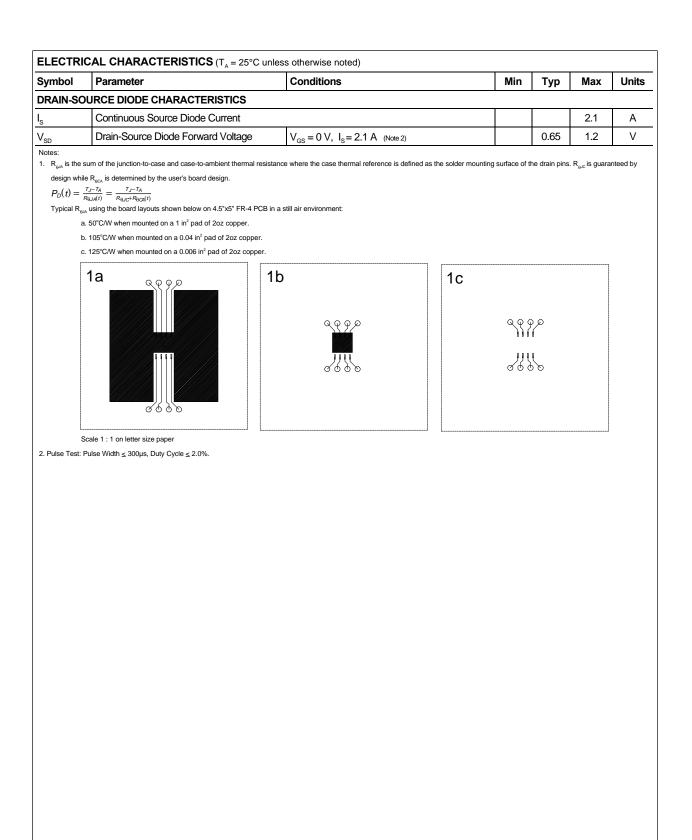


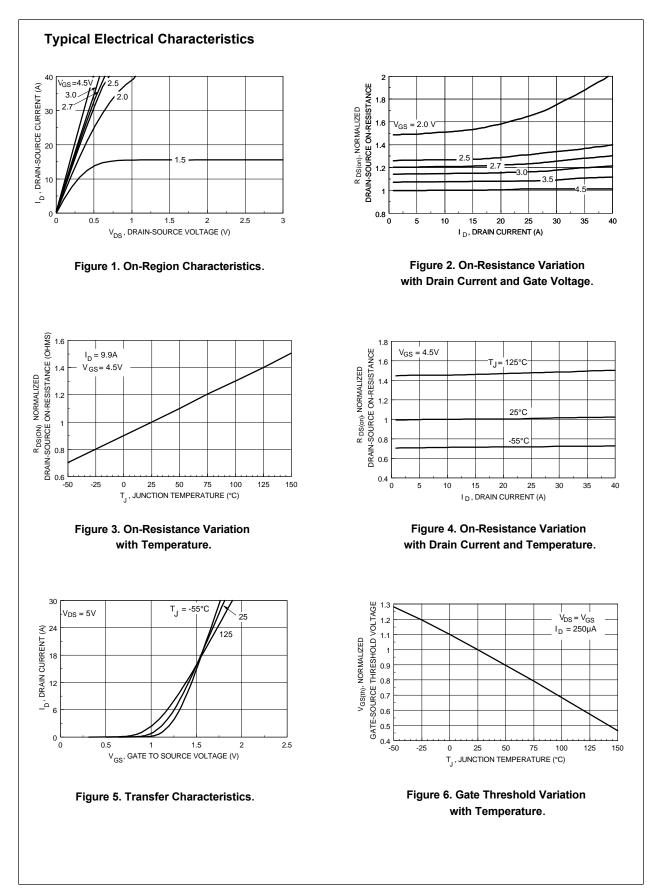
ABSOLUTE MAXIMUM RATINGS $T_A = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		NDS8426	Units
V _{DSS}	Drain-Source Voltage		20	V
V _{GSS}	Gate-Source Voltage		8	V
I _D	Drain Current - Continuous	(Note 1a)	9.9	A
	- Pulsed		20	
P _D	Maximum Power Dissipation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1	
Γj, T stg	Operating and Storage Temperature Range		-55 to 150	°C
THERMA	L CHARACTERISTICS			
۲ ^{θJA}	Thermal Resistance, Junction-to-Ambier	tt (Note 1a)	50	°C/W
۲ ^{өлс}	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W

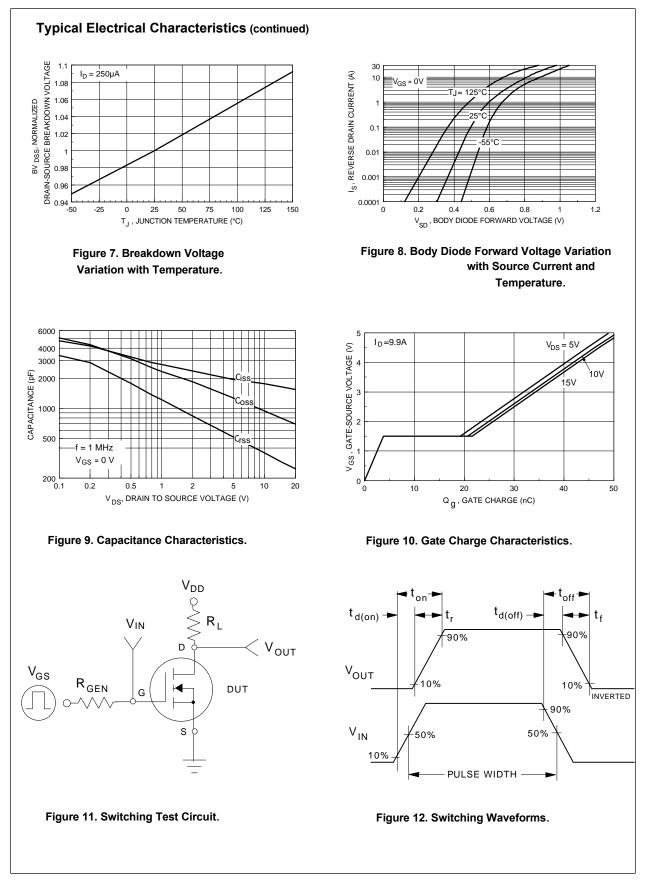
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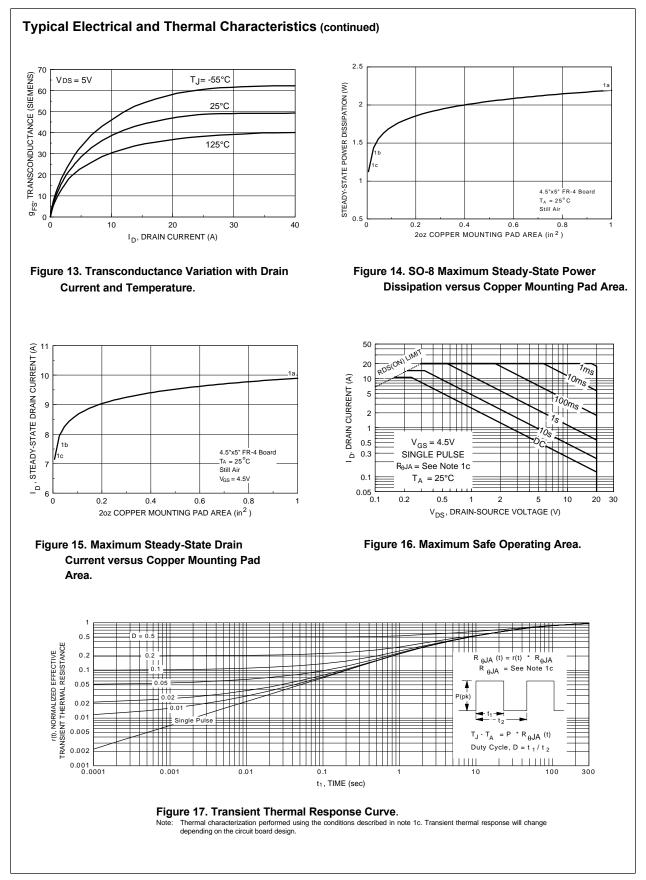
Symbol	Parameter	Conditions		Min	Тур	Мах	Units
OFF CHA	RACTERISTICS			•			•
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 250 \mu A$		20			V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 16 \text{ V}, V_{GS} = 0 \text{ V}$				1	μA
			T_= 55°C			10	μA
I _{GSSF}	Gate - Body Leakage, Forward	$V_{GS} = 8 V, V_{DS} = 0 V$				100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	V _{GS} = -8 V, V _{DS} = 0 V				-100	nA
ON CHAR	ACTERISTICS (Note 2)						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		0.4	0.6	1	V
			T_= 125°C	0.3	0.34	0.8	1
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_{D} = 9.9 \text{ A}$			0.013	0.015	Ω
			T_= 125°C		0.017	0.027	Ì
		$V_{GS} = 2.7 \text{ V}, I_{D} = 8.8 \text{ A}$			0.016	0.02	Ì
I _{D(on)}	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$		20			Α
9 _{FS}	Forward Transconductance	$V_{\rm DS} = 5 \text{ V}, \text{ I}_{\rm D} = 9.9 \text{ A}$			38		S
DYNAMIC	CHARACTERISTICS						
C _{iss}	Input Capacitance	$V_{DS} = 10 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$ f = 1.0 MHz			1765		pF
C _{oss}	Output Capacitance				940		pF
C _{rss}	Reverse Transfer Capacitance				360		pF
SWITCHIN	IG CHARACTERISTICS (Note 2)						
t _{D(on)}	Turn - On Delay Time	$V_{\text{DD}} = 5 \text{ V}, \text{ I}_{\text{D}} = 1 \text{ A},$ $V_{\text{GEN}} = 4.5 \text{ V}, \text{ R}_{\text{GEN}} = 6 \Omega$			15	30	ns
ţ.	Turn - On Rise Time				30	55	ns
t _{D(off)}	Turn - Off Delay Time				120	220	ns
t _r	Turn - Off Fall Time				58	100	ns
Q _g	Total Gate Charge	$\frac{V_{DS} = 10 \text{ V},}{I_D = 9.9 \text{ A}, V_{GS} = 4.5 \text{ V}}$			46	64	nC
Q _{gs}	Gate-Source Charge				3		nC
Q _{gd}	Gate-Drain Charge				18		nC

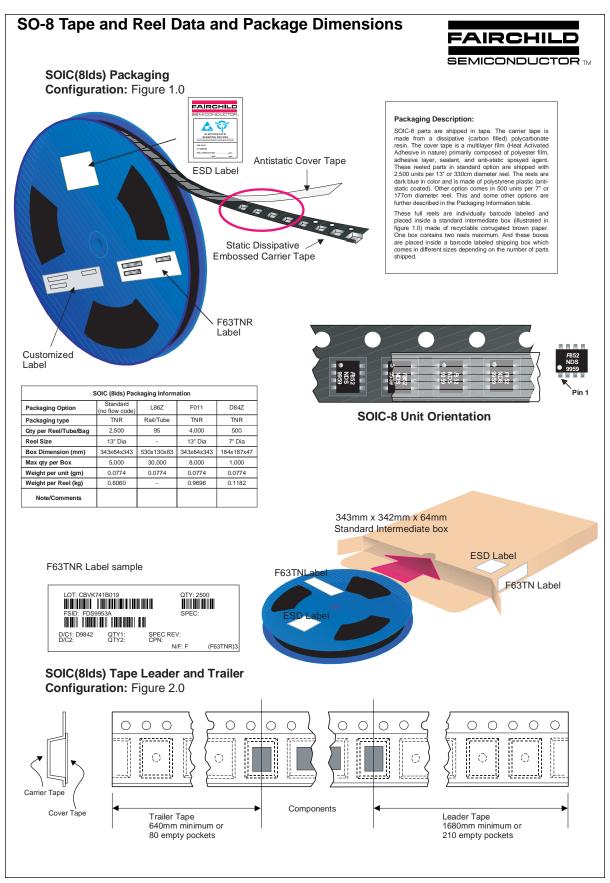




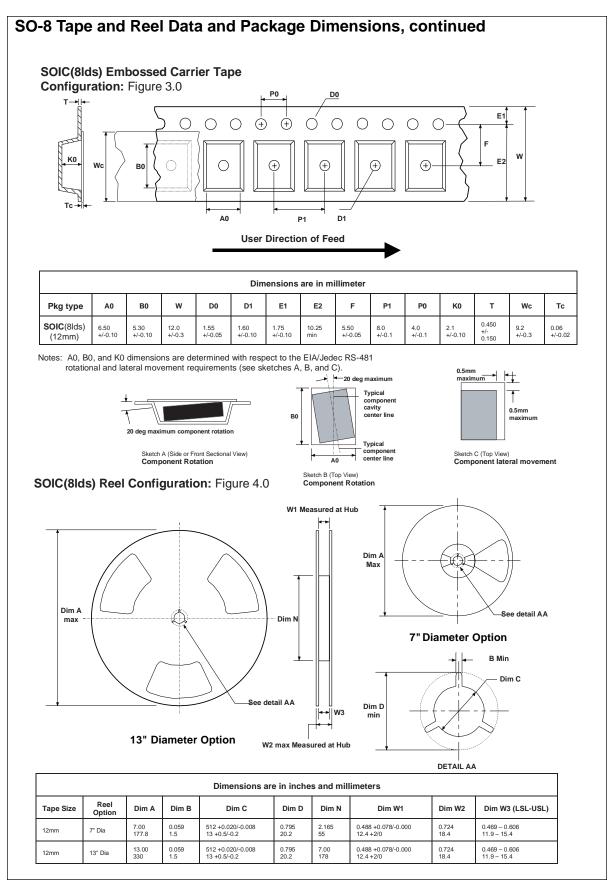
NDS8426 Rev.E

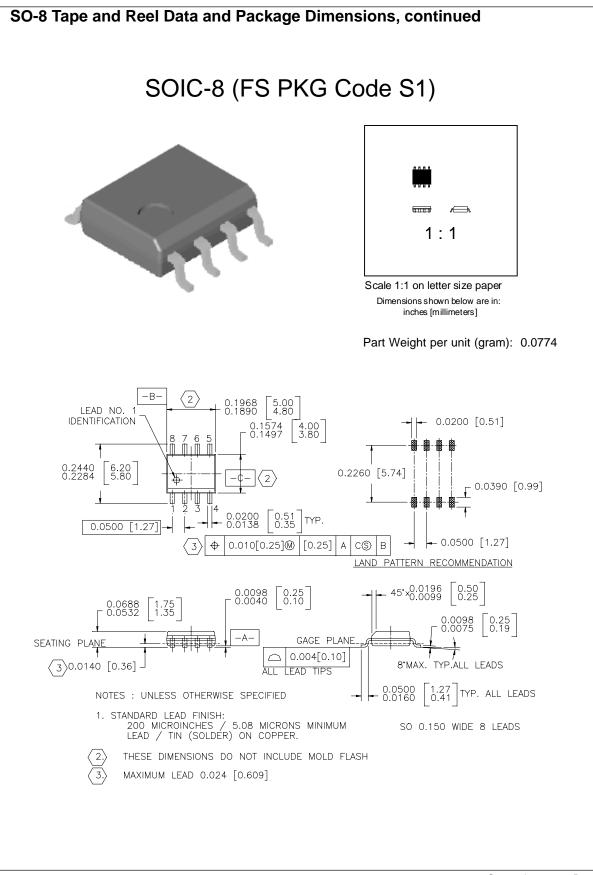






July 1999, Rev. B





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